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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/537,392	BARDELL ET AL.	
Examiner	Art Unit	
Benny Lee	2817	

SEARCHED			
Class	Subclass	Date	Examiner
315	5,5.38, 5.39,5.51	11/30/2007	BTL

INTERFERENCE SEARCHED				
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